# Grammar Investigation 

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## Grammar life cycle



## What to expect

$\sqrt{C}++$ is bigger than C .
$\checkmark \mathrm{C} \#$ is more complex than Java.
$\checkmark$ There are 11 bugs in Rascal.
$\checkmark$ Modula can have 2 sublanguages.
$\checkmark$ Fortran and Oberon are equally hard to learn.
$\checkmark$ It was more difficult to develop Rascal than XPath.
$\checkmark$ C\# grammar is hard to extend, can be improved.
$\checkmark$ JDK grammars underuse the grammar notation.

## What to recall

$\checkmark$ Formal grammars
$\checkmark$ Complexity theory
$\checkmark$ Software metrics
$\checkmark$ Mathematical statistics
$\checkmark$ Program impurity classes
$\checkmark$ Psychiatry
$\checkmark$ Software science
$\checkmark$ Lorenz curve
$\checkmark$ Control flow analysis
$\checkmark$ Product quality standard
$\checkmark$ Pattern recognition
$\checkmark$ Graph theory

## Grammar investigation

## Grammar

## Profit!

## Grammar investigation

## Usually a number

## Usually an indication or a forecast

## Motivation

$\checkmark$ Compare size and effort.
$\checkmark$ Estimate the quality of the grammar.
$\checkmark$ Predict future complications (detect smells).
$\checkmark$ Improve grammar quality.
$\checkmark$ Compare language implementations.
$\checkmark$ Evaluate productivity impacts of new techniques.

## What do metrics measure?

$\checkmark$ Eength Size
$\checkmark$ Quality, complexity
$\checkmark$ Language complexity
$\checkmark$ Structural complexity
$\checkmark$ Cognitive complexity, learnability
$\checkmark$ Functionality, usability
$\checkmark$ Defect density, reliability
$\checkmark$ Modularity, coupling/cohesion, reusability
$\checkmark$ Nobody knows exactly

## Grammar analysis

| $\begin{gathered} \hline \text { TERMI } \\ \text { VAR } \\ \text { LAB } \\ \text { PROD } \\ \text { DEAD } \\ \text { DEADP } \\ \text { UNDEF } \\ \text { ROOT } \\ \text { LOC } \\ \text { AVSN } \\ \text { AVSP } \end{gathered}$ | UMET <br> UOPS <br> MET <br> OPS <br> VOC <br> LEN <br> LEN^ <br> UOPS* <br> VOL <br> PVOL <br> BVOL <br> HLEV <br> HLEV^ <br> DIF, IC <br> LLEV <br> EFF <br> $\mathrm{EFF}{ }^{\wedge}$ BUG <br> BUG | NPAT <br> NPATC <br> MPAT <br> MPATC <br> WPAT <br> MCC <br> MI | FImin <br> Flavg <br> FImax <br> ONCE <br> FOmin <br> FOavg <br> FOmax <br> LEAF | LEV <br> CLEV <br> RLEV <br> NLEV <br> HEI <br> DEP <br> TIMPI <br> TIMP |
| :---: | :---: | :---: | :---: | :---: |

## Primitive grammar measurements

TERM
VAR
LAB
PROD
DEAD
DEADP
UNDEF
ROOT
LOC
AVSN
AVSP

## TERM: number of terminal symbols

$\checkmark$ Solid size metric
$\checkmark$ Easy to compute (traversal needed)
$\checkmark$ Almost no correlation with any other metrics (except, quite surprisingly, for NPAT)
$\checkmark$ TERM $\equiv 0$ for some meta-syntaxes (XSD, EMF)

## VAR: number of nonterminal symbols

$\checkmark$ Best to add the number of built-in primitives
$\checkmark$ Solid size metric
$\checkmark$ Easy to compute (traversal needed)
$\checkmark$ Extremely high correlation with most size metrics
$\checkmark$ Seems like a proper target for normalisations (except it is not, $r=0.9783$ )
$\checkmark$ Claims that "larger VAR implies greater maintenance overhead"

## LAB: number of descriptive labels

$\checkmark$ Expression selectors and production labels
$\sqrt{ }$ More of a documentation metric
$\checkmark$ Does it capture readability?
$\checkmark$ Easy to compute (traversal needed)
$\checkmark$ Being the only documentation metric, does not correlate with anything

## PROD: number of production rules

$\checkmark$ Trivial to compute (no traversal)
$\sqrt{ }$ Conceptually different from VAR, but always correlates heavily ( $r=0.9890$ )
$\checkmark$ It is known that:

$\mathrm{VAR} \leq \mathrm{PROD}$

## DEAD: number of dead nonterminals

$\checkmark$ Nonterminal symbols unreachable from the root
$\checkmark$ Easy to compute (traversal)

## DEADP: number of dead productions

$\checkmark$ Production rules unreachable from the root
$\checkmark$ Relatively easy to compute (traversal)

## UNDEF: number of bottom nonterminals

$\checkmark$ Nonterminals that are used but not defined
$\checkmark$ Relatively easy to compute (traversal)

## ROOT: number of start symbols

$\checkmark$ In theory, one and only one start
$\checkmark$ In practice, multiple or none are possible
$\checkmark$ Trivial to compute (no traversal)

## LOC: lines of EBNF code

$\checkmark$ Following LOC counting traditions
$\checkmark$ Secondary metric computed as:

$$
\mathrm{LOC}=\mathrm{VAR}+\mathrm{PROD}
$$

## AVSN: average right hand side size

$\sqrt{ }$ Per nonterminal symbol
$\checkmark$ Relatively easy to compute

## AVSP: average right hand side size

$\checkmark$ Per production rule
$\checkmark$ Relatively easy to compute

## Grammarware science

UMET
UOPS
IMET
OPS
VOC
LEN
LEN^
UOPS*
VOL
PVOL
BVOL
HLEV
HLEV^
DIF, IC
LLEV
EFF
EFF^
BUG

## UMET: unique meta-symbols

$\checkmark$ Tells more about grammar notation
$\sqrt{ }$ Or about the extent to which notation is exercised
$\checkmark$ For the notation, there exists UMET:

$$
2 \leq \mathrm{UMET} \leq \underline{\mathrm{UMET}}
$$

## UOPS: unique operands

$\checkmark$ Can be computed as:

$$
\mathrm{UOPS}=\mathrm{VAR}+\mathrm{TERM}+\mathrm{LAB}
$$

$\checkmark$ There exists UOPS*:

$$
\text { UOPS* } \leq \text { UOPS }
$$

## UOPS*: minimum required operands

$\sqrt{ }$ Can be computed as:
UOPS* = TERM + ROOT + UNDEF
$\checkmark$ If the above expression is zero, 2nd assumption:
UOPS* = DEAD

## MET: used metasymbols

$\checkmark$ Number of applications of sequential composition, repetition, optionality, ...
$\checkmark$ Known property:

## $\mathrm{UMET} \leq \mathrm{MET}$

## OPS: used operands

$\checkmark$ Number of occurrences of nonterminals, terminals, labels, ...
$\checkmark$ Known property:

$$
\mathrm{UOPS} \leq \mathrm{OPS}
$$

## VOC: grammar vocabulary

$\sqrt{ }$ Can be computed as:

$$
\mathrm{VOC}=\mathrm{UMET}+\mathrm{UOPS}
$$

## LEN: grammar length

$\sqrt{ }$ Can be computed as:
LEN = MET + OPS

## PUR: purity ratio

$\checkmark$ Can be computed as:

$$
\mathrm{PUR}=\widehat{\mathrm{LEN}} / \mathrm{LEN}
$$

## VOL: grammar volume

$\sqrt{ }$ Can be computed as:

$$
\mathrm{VOL}=\mathrm{LEN} \log _{2} \mathrm{VOC}
$$

## PVOL: potential (minimal) volume

$\checkmark$ Can be computed as:

$$
\text { PVOL }=(2+\text { UOPS } *) \log _{2}(2+\text { UOPS* })
$$

## BVOL: boundary volume

$\sqrt{ }$ Can be computed as:

$$
\mathrm{BVOL}=\left(2+\mathrm{UOPS}^{*} \log _{2} \mathrm{UOPS}^{*}\right) \log _{2}\left(2+\mathrm{UOPS}^{*}\right)
$$

## HLEV: grammar level

$\sqrt{ }$ Can be computed as:

## HLEV: PVOL/VOL

$\checkmark$ Known property:

$$
0 \leq \mathrm{HLEV} \leq 1
$$

## HLEV: estimated grammar level

$\checkmark$ Can be computed as:

$$
\widehat{\mathrm{HLEV}}:(2 \times \mathrm{UOPS}) /(\mathrm{UMET} \times \mathrm{OPS})
$$

## DIF: difficulty

$\sqrt{ }$ Can be computed as:
DIF $=1 / \mathrm{HLEV}$

## LLEV: meta-language level

$\checkmark$ Can be computed as:
LLEV = HLEV×PVOL
$\checkmark$ For English: 2.16
$\checkmark$ For Algol: 1.21
$\checkmark$ For Assembly: 0.88
$\checkmark$ For BNF: 0.00002-0.00437

## EFF: engineering effort

$\sqrt{ }$ Can be computed as:

> EFF = VOL/HLEV

## $\widehat{\text { EFF: }}$ estimated engineering effort

$\checkmark$ The most commonly used metric "by Halstead"
$\checkmark$ Was not suggested by Maurice Halstead.
$\checkmark$ Computed as:
$\widehat{\mathrm{EFF}}=\frac{\mathrm{VOL}}{\widehat{\mathrm{HLEV}}}=\frac{\mathrm{UMET} \times \mathrm{OPS} \times \mathrm{LEN} \times \log _{2} \mathrm{VOC}}{2 \times \mathrm{UOPS}}$

## BUG: estimated number of errors

$\sqrt{ }$ Can be computed as:

$$
\mathrm{BUG}=\mathrm{EFF}^{2 / 3} / 3000
$$

$\checkmark$ Or (more accurate):

$$
\mathrm{BUG}=\mathrm{VOL} / 3000
$$

Pattern (clone type II) analysis
NPAT NPATC MPAT MPATC WPAT

## NPAT: number of patterns

$\checkmark$ Conceptual clone detection
$\checkmark$ Map all productions to $\{\mathrm{N}, \mathrm{T},(), \mid\}^{*}$
$\checkmark$ It is known that:

$$
1 \leq \text { NPAT } \leq \text { PROD }
$$

## NPATC: normalised NPAT

$\sqrt{ }$ Computed as:

$$
\text { NPATC }=\text { NPAT } / \text { PROD } \times 100 \%
$$

$\checkmark$ It is obvious that:

$$
\mathrm{PROD}^{-1} \leq \mathrm{NPATC} \leq 1
$$

## MPAT: max number of pattern uses

$\sqrt{ }$ It is obvious that:

$$
1 \leq \mathrm{MPAT} \leq \mathrm{PROD}
$$

## MPATC: normalised MPAT

$\sqrt{ }$ Computed as:

$$
\text { MPATC }=\mathrm{MPAT} / \mathrm{PROD} \times 100 \%
$$

$\checkmark$ It is obvious that:

$$
\mathrm{PROD}^{-1} \leq \mathrm{MPATC} \leq 1
$$

## WPAT: length of the longest pattern

$$
0 \leq \mathrm{WPAT}<\infty
$$

$\checkmark \exists$ NPAT $^{*}$ : max number of patterns

$$
\text { NPAT } \leq \text { NPAT }^{*}
$$

| WPAT | NPAT* |
| :---: | :---: |
| 0 | 1 |
| 1 | 3 |
| 2 | 7 |
| 3 | 21 |
| 4 | 73 |
| 5 | 279 |
| $\ldots$ | $? ? ?$ |

## Control flow (fan-in \& fan-out)



## Nonterminal fan-in

$\checkmark$ Number of uses of a nonterminal within a grammar
$\checkmark$ Fan-in $=0 \Rightarrow$ DEAD
$\checkmark$ Fan-in $=1 \Rightarrow$ ONCE

## FImin $\geq 2$

$$
0 \leq \text { FIavg } \leq \text { FImax } \leq \text { VAR }
$$

$\checkmark$ Coupling metric

## Nonterminal fan-out

$\checkmark$ Number of distinct nonterminals referenced
$\checkmark$ Fan-out $=0 \Rightarrow$ LEAF
FOmin $\geq 1$

$$
0 \leq \text { FOavg } \leq \text { FOmax } \leq \mathrm{VAR}
$$

$\checkmark$ Cohesion metric
$\checkmark$ If $\mathrm{VAR}=\mathrm{PROD}$,
FOmax $\leq$ WPAT

## Grammatical levels \& call graph



## LEV: number of grammatical levels

$\checkmark$ Grammatical level: a subset of mutually dependent nonterminals
$\checkmark$ It is known that:

$$
1 \leq \mathrm{LEV} \leq \mathrm{VAR}
$$

## CLEV: percentage of gram.levels

$\checkmark$ LEV normalised by nonterminal count
$\checkmark$ Computed as:

$$
\mathrm{CLEV}=\mathrm{LEV} / \mathrm{VAR} \times 100 \%
$$

$\checkmark$ Low $\mathrm{CLEV} \Rightarrow$ nonterminals are clustered into few equivalence classes, subjects to modularisation

## RLEV: number of recursive levels

$\checkmark$ Levels that are either nontrivial or self-referring
$\checkmark$ It is known that:

$$
0 \leq \text { RLEV } \leq \text { LEV }
$$

$\checkmark$ RLEV reveals the number of syntactic components
$\checkmark$ RLEV $=0 \Leftrightarrow$ the language is finite

## NLEV: number of nontrivial levels

$\checkmark$ Levels that consist of more than one nonterminal
$\checkmark$ It is known that:

$$
0 \leq \text { NLEV } \leq \text { RLEV }
$$

## DEP: depth

$\checkmark$ The size of the biggest grammatical level
$\sqrt{ }$ It can be proven that:

$$
\mathrm{DEP} \leqslant \frac{\mathrm{VAR}-\mathrm{LEV}}{\mathrm{NLEV}}+1
$$

$\sqrt{ }$ High DEP indicates uneven distribution of nonterminals among grammatical levels
$\checkmark$ The distribution is always uneven!

## HEI: Varju height

$\checkmark$ The longest path from the starting gram.level
$\sqrt{ }$ It is known that:

## $\mathrm{HEI} \leq \mathrm{LEV}$

$\checkmark$ All metrics derived from grammatical levels are pairwise strongly independent on the class of context-free languages.

## TIMPI: (immediate) tree impurity

$\checkmark$ A call graph is always between a tree and a complete digraph
$\checkmark$ How far is the immediate call graph from a tree?

$$
\text { TIMP }=\frac{e-n+1}{n(n-1)} 100 \%
$$

$\checkmark$ where $n$ is the number of nodes (nonterminals) and $e$ is the number of edges


## TIMP: tree impurity

$\checkmark$ A closure on the call graph is always between a tree and a complete digraph
$\checkmark$ How far is it from a tree?
$\checkmark$ Obviously,

## TIMPI $\leq$ TIMP

$\checkmark$ Correlates well with CLEV
$\checkmark$ It is claimed that high TIMP hinders adaptation

## Cyclomatic complexity

## MCC: cyclomatic complexity

$\checkmark$ McCabe, McClure
$\checkmark$ Number of decision points:
$\checkmark$ choices
$\checkmark$ optionality
$\checkmark$ repetition
$\checkmark$ Other cyclomatic metrics exist
$\checkmark$ To be explored

## Maintainability index

## MI: maintainability index

$\checkmark$ Coleman-Oman model
$\checkmark$ Secondary metric computed as:
$\mathrm{MI}=171-5.2 \ln$ VOL $-0.23 \mathrm{MCC}-16.2 \ln \mathrm{LOC}$
$\checkmark$ Observed considerable reverse correlation with the first BUG metric ( $r=-0.9080$ )

## Grammar analysis

| $\begin{gathered} \hline \text { TERMI } \\ \text { VAR } \\ \text { LAB } \\ \text { PROD } \\ \text { DEAD } \\ \text { DEADP } \\ \text { UNDEF } \\ \text { ROOT } \\ \text { LOC } \\ \text { AVSN } \\ \text { AVSP } \end{gathered}$ | UMET <br> UOPS <br> MET <br> OPS <br> VOC <br> LEN <br> LEN^ <br> UOPS* <br> VOL <br> PVOL <br> BVOL <br> HLEV <br> HLEV^ <br> DIF, IC <br> LLEV <br> EFF <br> $\mathrm{EFF}{ }^{\wedge}$ BUG <br> BUG | NPAT <br> NPATC <br> MPAT <br> MPATC <br> WPAT <br> MCC <br> MI | FImin <br> Flavg <br> FImax <br> ONCE <br> FOmin <br> FOavg <br> FOmax <br> LEAF | LEV <br> CLEV <br> RLEV <br> NLEV <br> HEI <br> DEP <br> TIMPI <br> TIMP |
| :---: | :---: | :---: | :---: | :---: |

## Recall complexity theory

$\checkmark$ Kolmogorov complexity is about how much resources are needed to specify the entity.
$\checkmark$ The shortest description in a meta-language.
$\checkmark$ Hence, related to normal forms.
$\checkmark$ Also linked to identifiable structured subentities.
$\checkmark$ Complexity is incomputable.
$\checkmark$ All proof systems have a complexity threshold.

## Metrics tripled

$\checkmark$ Measure working/baseline/recovered grammars
$\checkmark$ Measure normalised grammars
$\checkmark$ Impurity V "Unwarranted Assignment"
$\checkmark$ Impurity VI "Unfactored Expressions"
$\checkmark$ Measure freshly extracted grammars
$\checkmark$ May be incorrect, contain dead production rules
$\checkmark$ Easier to get than good quality grammars

## Grammar normalisations

$\sqrt{ }$ Chain productions
$\checkmark$ Remove (xbgf:unchain)
$\sqrt{ }$ Nonterminals that are used only once
$\checkmark$ Unfold (xbgf:inline)
$\sqrt{ }$ Definitions that contain unfactored expressions
$\checkmark$ Factor (xbgf:distribute)

## Idea: some metrics tell the same story

$\checkmark$ Gather statistical data
$\checkmark$ Compute correlations

$$
r_{x y}=\frac{\sum\left(x_{i}-\bar{x}\right)\left(y_{i}-\bar{y}\right)}{\sqrt{\sum\left(x_{i}-\bar{x}\right)^{2} \sum\left(y_{i}-\bar{y}\right)^{2}}}
$$

$\checkmark$ Research how normalisation changes results
$\checkmark$ Research what metrics are heavily interdependent
$\checkmark \Rightarrow$ measure the same thing

## How to compare a metric with itself?

$\checkmark$ Not looking for a correlation with itself ( $r \equiv 1.0$ )
$\checkmark$ How interesting are the results provided by a metric?
$\checkmark$ Constants are not interesting
$\checkmark$ "Linear" metrics will be detected by their correlation with size (VAR, PROD , ...) anyway
$\checkmark$ Versatile results are interesting!
$\checkmark$ Deviation? Variance?

## Gini coefficients

$\sqrt{ }$ Measure the inequality of a distribution
$\sqrt{ } \mathrm{G}=0 \Rightarrow$ total equality
$\sqrt{ } \mathrm{G}=1 \Rightarrow$ total inequality
$\checkmark$ Adjust the formula for our needs:

$$
g_{x}=\frac{2}{n}\left(n-\frac{1+\sum i x_{i}}{\sum x_{i}}\right)
$$

## Gini coeff: MPATC ( $\mathrm{g}=0.8588$ )



## Gini coeff: RLEV (g=0.3535)



## Freshly extracted grammars

> TERM' VAR' LAB' PROD' DEAD'
> DEADP' UNDEF' AVSP' HLEV' WPAT'

## Normalised grammars

~AVSN ~AVSP ~HLEV^ ~NPATC ~MPATC ~WPAT
$\sim$ FImin
${ }^{\sim}$ FImax
~FOmin
~FOmax
~TIMPI
~TIMP
${ }^{\sim}$ MCC

## Interesting things found

$\checkmark$ A cluster of plain size metrics (farther from TERM $\Leftrightarrow$ closer to VAR)
$\checkmark$ LEAF complements NPAT and correlates with size metrics that are far from VAR: $\widehat{\text { LEN, }}$, VOC, UOPS, ...
$\checkmark$ VAR correlates with PROD $(r=0.9890)$
$\checkmark$ AVSN does not correlate with AVSP (???)
$\checkmark$ MI reverse correlates with $\mathrm{BUG}^{1}$
$\checkmark$ LEV correlates with maximum fan-in (???)
$\sqrt{ }$ CLEV and TIMP display strong reverse correlation

## Complete picture (47/159)

| $\begin{aligned} & \text { TERM' } \\ & \text { VAR' } \\ & \text { LAB' } \\ & \text { PROD' } \\ & \text { DEAD' } \\ & \text { DEADP' } \\ & \text { UNDE' ' } \\ & \text { AVSP' } \\ & \text { HLEV' } \\ & \text { WPAT' } \end{aligned}$ | TERM VAR LAB PROD <br> DEADP UNDEF ROOT AVSN AVSP | UMET <br> UOPS <br> MET <br> OPS <br> VOC <br> LEN <br> UOPSS* <br> VOL <br> PVOL <br> BVOL <br> HLEV <br> DIF, IC <br> LLEV <br> EFF EFF^ BUG | NPAT <br> NPATC <br> IMPAT <br> MPATC <br> WPAT <br> MCC <br> ... | FImin <br> FTavg <br> FImax <br> ONCE <br> FOmin <br> FOavg <br> FOmax <br> LEAF | $\begin{gathered} \hline \text { LEV } \\ \text { CLEV } \\ \text { RLEV } \\ \text { NLEV } \\ \text { HEI } \\ \text { DEP } \\ \text { TIMMPI } \\ \text { TIMMP } \end{gathered}$ |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |

## Threat to validity



## Static vs interactive

$\checkmark$ Top nonterminals
$\checkmark$ Top nonterminals list count
$\checkmark$ Average production length
$\checkmark$ Number of subcomponents
$\sqrt{ }$ Productions that are too long
$\sqrt{ }$ Indication on how to extract modules from subcomponents

Complex measurements: fan-in
O. JDK $1.0 \mathrm{impl} \quad 0$ JDK 1.0 read

- J2SE 1.2 impl O. J2SE 1.2 read
- J2SE 5.0 impl O. J2SE 5.0 read


## Complex measurements: fan-in

O. JDK $1.0 \mathrm{impl} \quad$ O. JDK 1.0 read

- J2SE 1.2 impl O J2SE 1.2 read
- J2SE 5.0 impl O. J2SE 5.0 read


## ONCE

## DEAD



## Complex measurements: fan-out



## ; Complex measurements: patterns

- FL in DCG
- EBNF in SDF
- PICO in SDF
- FL in Java
- BNF in SDF
- BTF in XSD
- FL in SDF
- YACC in SDF
- LCF in XSD
- FL in XSD
- FL in Ecore
- LOGO in SDF
- FL in TXL
- FL in ANTLR
- FL in Ecore/XSD
- FL in XSD/Java
- BGF in XSD


## Complex measurements: patterns

$\sqrt{ }$ The most popular patterns found in all grammars:

| Pattern | Uses everywhere | Uses everywhere |
| :---: | :---: | :---: |
| $N$ | 2682 | 1635 |
| $T$ | 1724 | 1198 |
| NTN | 664 | 671 |
| NN | 346 | 277 |
| $T N$ | 252 | 212 |
| $T N T$ | 150 | 136 |
| $T\{N\} T$ | 134 |  |
| $N\{N\}$ | 107 | 68 |
| $N T$ | 100 | 85 |
| $T T N$ | 100 | 75 |

## Dynamic measurements: call graph



## Unsolved questions

$\sqrt{ }$ Performance

| Extract/recover grammarbase | $5: 23$ |
| :--- | :---: |
| Normalise grammars | $10: 19$ |
| Calculate correlations between rec \& ext, rec \& num | $3: 06$ |
| Calculate all possible correlations | $4: 35$ |
| Calculate Gini coefficients | $2: 04$ |
| Compute metrics | $1: 24$ |

## Unsolved questions

$$
r(C L E V, T I M P)=0.9518
$$

$\sqrt{ }$ The relation between the number of cliques in a directed graph normalised per number of nodes, and the distance of that graph from being a tree?

## Unsolved questions

$\checkmark$ The Coleman-Oman maintainability model is wrong.
$\checkmark$ Normalisation as explained (unchain/inline/factor)
$\checkmark$ reduces analysability
$\checkmark$ reduces changeability
$\checkmark$ reduces testability
$\sqrt{ }$ increases the maintenance index
$\checkmark$ Contradiction with ISO 9126

## Unsolved questions

$\checkmark$ Completeness claims (the lack thereof).
$\checkmark$ When can we tell that we have measured everything?
$\checkmark$ When should we just stop measuring everything?

## Awesome things ahead

$\checkmark$ Preserving properties of trafo/normalisations
$\checkmark$ Dynamic grammar analysis
$\checkmark$ Grammar smells
$\checkmark$ Metrics for pairs of grammars
$\checkmark$ Coverage metrics for grammar testing
$\checkmark$ Metrics for grammar transformations

## To do

$\checkmark$ Better classification: measure, metric, counter, ...
$\checkmark$ Formulae related or values related?
$\checkmark$ Information flow metrics
$\checkmark$ Parsing influences by metrics
$\checkmark$ More research on normal form theory
$\checkmark$ More indicators
$\checkmark$ Feedback?

